

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|--|--|------------------|---------|------------------|
| L2 | 1295 | 702/182.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/02/13 13:41 |
| L3 | 641 | 700/108.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/02/13 13:43 |
| L6 | 6 | (manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near\$4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments).clm. | US-PGPUB | OR | ON | 2006/02/13 13:48 |
| L7 | 1 | 3 and 6 | US-PGPUB | OR | ON | 2006/02/13 13:48 |
| L8 | 2 | 2 and 6 | US-PGPUB | OR | ON | 2006/02/13 13:48 |
| S1 | 3 | manufactur\$4 and ((yield\$1 or production) with (loss or low) with time with period) and ((detect\$3 or identif\$4 or determin\$3 or monitor\$3) with (stability or fail\$3 or disorder or breakdown) with (machine\$1 or apparatus\$1 or instrument\$1 or press or device\$1)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:51 |
| S2 | 1314 | (manufactur\$4 or fabricating) and ((yield\$1 or product\$5) with (loss or low or fail\$3) with time with period) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:08 |
| S3 | 44 | S2 and ((detect\$3 or identif\$4 or determin\$3 or monitor\$3 or inspect\$3) with (stability or fail\$3 or disorder or breakdown) with (machine\$1 or apparatus\$1 or instrument\$1 or press or device\$1)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 16:20 |
| S4 | 28831 | ((detect\$3 or identif\$4 or determin\$3 or monitor\$3 or inspect\$3 or examin\$3) with (stability or fail\$4 or fault\$1 or disorder or breakdown or disabl\$3 or quality or (low\$2 with yield\$1))) and ((machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with ((production adj line) or parallel)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:10 |
| S5 | 37 | S4 and S2 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 16:43 |
| S6 | 513 | (manufactur\$4 or fabricating or product\$3) and (yield\$1 with low\$2 with time with period) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:18 |

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|-----|--------|--|--|----|-----|------------------|
| S7 | 31 | (machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line) with parallel with plurality | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:13 |
| S8 | 0 | S6 and S7 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:11 |
| S9 | 63531 | (machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with parallel with plurality | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:12 |
| S10 | 1 | S6 and S9 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:12 |
| S11 | 606 | (machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line) with plurality | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:20 |
| S12 | 1 | S6 and S11 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:13 |
| S13 | 529 | (manufactur\$4 or fabricating or product\$3) and ((yield\$1 or (production adj rate\$1)) with low\$2 with time with period) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:23 |
| S14 | 12262 | (machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:36 |
| S15 | 9 | S13 and S14 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:20 |
| S16 | 107987 | (manufactur\$4 or fabricating or product\$3) and ((yield\$1 or (production adj rate\$1)) with low\$2) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:37 |
| S17 | 224 | S14 and S16 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:23 |

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| S18 | 0 | S17 and (downward with tendency) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:27 |
| S19 | 2335 | (downward with tendency) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:24 |
| S20 | 10 | S14 and S19 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:25 |
| S21 | 4 | S17 and ((history or tendency or trend) with yield\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:37 |
| S22 | 15320 | (machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with ((production or manufactur\$3) adj line) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:49 |
| S23 | 319 | S22 and S16 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:37 |
| S24 | 13 | S23 and ((history or tendency or trend) with yield\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 17:40 |
| S25 | 1 | S22 and (low adj yield adj period) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2004/12/18 19:22 |
| S26 | 987 | 702/182.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 14:01 |
| S27 | 2 | "5274434".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/01/03 15:44 |
| S28 | 2 | "4357574".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/01/03 15:45 |

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| S29 | 3 | "6611728".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/01/04 15:15 |
| S30 | 2 | "20020143483" | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/01/04 15:16 |
| S31 | 2 | "20030176939" | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/01/04 15:16 |
| S32 | 136910 | (production or manufactur\$3 or fabrication) and (semiconductor or semi adj conductor or wafer\$1) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1 or press or device\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:23 |
| S33 | 1596 | S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2 or decreas\$3 or increas\$3) with (time or period\$1)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 13:43 |
| S34 | 932 | S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2) with (time or period\$1)) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 13:44 |
| S35 | 72 | S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:25 |
| S36 | 253190 | (production or manufactur\$3 or fabrication) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:34 |
| S37 | 214 | S36 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2 or defect\$3 or fail\$3) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:35 |
| S38 | 207097 | (manufactur\$3 or fabrication) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:34 |
| S39 | 174 | S38 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2 or defect\$3 or fail\$3) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:36 |

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| S40 | 92 | S38 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/27 14:46 |
| S41 | 37 | (manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:56 |
| S42 | 633 | 702/108.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:51 |
| S43 | 342 | 356/237.4.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:51 |
| S44 | 37 | (manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 14:02 |
| S45 | 0 | S42 and S44 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:57 |
| S46 | 0 | S43 and S44 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:57 |
| S47 | 0 | 700/108.ccls | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:58 |
| S48 | 592 | 700/108.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/02/13 13:43 |
| S49 | 6 | S44 and S48 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:59 |

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| S50 | 1202 | 702/182.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2006/02/13 13:41 |
| S51 | 3 | S44 and S50 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 14:01 |
| S52 | 4 | (manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near\$4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments).clm. | US-PGPUB | OR | OFF | 2006/02/13 13:40 |
| S53 | 1 | S50 and S52 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 14:03 |
| S54 | 0 | S47 and S52 | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 14:03 |